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APPLICATION NO.	FILING DAT	FIRST NAMED INVENTOR	ATTORNEY DOCKET NO.	CONFIRMATION NO
09/935,255	08/22/2001	Ronald A. Weimer	MTI-31529	1208
31870	7590 01/1	005	EXAMINER	
	IRSCHBOECK	CHEN, JACK S J		
555 EAST WELLS STREET SUITE 1900 MILWAUKEE, WI 53202			ART UNIT	PAPER NUMBER
			2813	
			DATE MAILED: 01/11/200	5

Please find below and/or attached an Office communication concerning this application or proceeding.

		Application No.	Applicant(s)			
Office Action Summary		09/935,255	WEIMER, RONALD A.			
		Examiner	Art Unit			
		Jack Chen	2813			
The MAILING DATE of this communication appears on the cover sheet with the correspondence address Period for Reply						
THE - Exte after - If the - If NC - Failu Any	ORTENED STATUTORY PERIOD FOR REPLY MAILING DATE OF THIS COMMUNICATION. nsions of time may be available under the provisions of 37 CFR 1.13 SIX (6) MONTHS from the mailing date of this communication. be period for reply specified above is less than thirty (30) days, a reply period for reply is specified above, the maximum statutory period vare to reply within the set or extended period for reply will, by statute, reply received by the Office later than three months after the mailing ed patent term adjustment. See 37 CFR 1.704(b).	36(a). In no event, however, may a reply be time within the statutory minimum of thirty (30) days will apply and will expire SIX (6) MONTHS from a cause the application to become ABANDONEI	nely filed s will be considered timely. the mailing date of this communication. O (35 U.S.C. § 133).			
Status						
1)	Responsive to communication(s) filed on					
′=	· —	action is non-final.				
3)	Since this application is in condition for allowance except for formal matters, prosecution as to the merits is closed in accordance with the practice under <i>Ex parte Quayle</i> , 1935 C.D. 11, 453 O.G. 213.					
Dispositi	ion of Claims					
5)	<ul> <li>4)  Claim(s) 1-57 and 73-121 is/are pending in the application.</li> <li>4a) Of the above claim(s) is/are withdrawn from consideration.</li> <li>5)  Claim(s) is/are allowed.</li> <li>6)  Claim(s) is/are rejected.</li> <li>7)  Claim(s) is/are objected to.</li> <li>8)  Claim(s) 1-57, 73-121 are subject to restriction and/or election requirement.</li> </ul>					
Applicati	ion Papers					
9)☐ The specification is objected to by the Examiner.						
10)☐ The drawing(s) filed on is/are: a)☐ accepted or b)☐ objected to by the Examiner.						
	Applicant may not request that any objection to the drawing(s) be held in abeyance. See 37 CFR 1.85(a).					
11)	Replacement drawing sheet(s) including the correct The oath or declaration is objected to by the Ex	,	, ,			
Priority (	under 35 U.S.C. § 119					
<ul> <li>12) Acknowledgment is made of a claim for foreign priority under 35 U.S.C. § 119(a)-(d) or (f).</li> <li>a) All b) Some * c) None of:</li> <li>1. Certified copies of the priority documents have been received.</li> <li>2. Certified copies of the priority documents have been received in Application No.</li> <li>3. Copies of the certified copies of the priority documents have been received in this National Stage application from the International Bureau (PCT Rule 17.2(a)).</li> <li>* See the attached detailed Office action for a list of the certified copies not received.</li> </ul>						
Attachmen	t(s)					
	e of References Cited (PTO-892)	4) Interview Summary				
3) 🔲 Infori	te of Draftsperson's Patent Drawing Review (PTO-948) mation Disclosure Statement(s) (PTO-1449 or PTO/SB/08) er No(s)/Mail Date	Paper No(s)/Mail Da 5) Notice of Informal P 6) Other:	atent Application (PTO-152)			

## **DETAILED ACTION**

The Office Action dated on 6 June 2004 is withdrawn upon further reconsideration of the instant application and in view of the communication dated on 28 October 2004. Claims 1-57 and 73-121 are active in this application.

## Election/Restrictions

- 1. Restriction to one of the following inventions is required under 35 U.S.C. 121:
  - I. Claims 1-27, 73-85 and 97-112, drawn to method for forming nitride barrier layer, classified in class 148, subclass 33.3.
  - II. Claims 28-41, drawn to method for forming nitride barrier layer in a semiconductor device, classified in class 438, subclass 791.
  - III. Claims 42-57, 86-96 and 113-121, drawn to method for forming a transistor gate stack having a nitride barrier layer in the gate dielectric, classified in class 438, subclass 585.

The inventions are distinct, each from the other because of the following reasons:

2. Inventions I, II and III are related as subcombinations disclosed as usable together in a single combination. The subcombinations are distinct from each other if they are shown to be separately usable. In the instant case, invention I has separate utility such as a barrier layer to protect metal cutting tools from corrosion due to moisture. Invention II has separate utility such as a barrier layer to prevent hydrogen diffusion into a high-k ferroelectric capacitor (FeRAM) during hydrogen annealing. See MPEP § 806.05(d).

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3. Because these inventions are distinct for the reasons given above and have acquired a

separate status in the art as shown by their different classification, restriction for examination

purposes as indicated is proper.

4. Because these inventions are distinct for the reasons given above and the search required

among the groups is divergent, restriction for examination purposes as indicated is proper.

5. This application contains claims directed to the following patentably distinct species of

the claimed invention:

Should Applicant elected the invention of Group I, then one from each of the following

groups must be elected:

IA. Method for forming silicon layer (see specification, pp. 2, 6-7)

IA-1. PECVD

IA-2. LPCVD

IA-3. RTCVD

IA-4. Thermal CVD

IA-5. CVD

IB. Method for forming nitride barrier layer (See specification, pp. 7)

IB-1. by thermally annealing in nitrogen-containing species (i.e., see abstract section)

IB-2. by exposing to plasma source (i.e., see abstract section)

IC. Silicon (See specification, pp. 2, 6)

IC-1. Polysilicon

IC-2. Amorphous silicon

ID. Dielectric layer (See specification, pp. 6)

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- ID-1. Silicon dioxide
- ID-2. Tantalum pentoxide
- ID-3. Hafnium dioxide
- ID-4. Aluminum trioxide
- IE. Silicon source materials (See specification, pp. 6)
  - IE-1. SiH2
  - IE-2. Si2H7
  - IE-3. SiH2Cl2
  - IE-4. SiCl4
  - IE-5. SiH4
  - IE-5. Si2H6

Currently, no claim is generic to the invention of Group I. Applicant is referred to MPEP 806.04(c) and 806.04(d) for the definition of a generic claim.

Should Applicant elected the invention of IB-1 (Nitrogen-containing gases) within IB, then one of the following species must be elected:

- IB-1-1. Using N2 as the nitrogen-containing gas
- IB-1-2. Using NH3 as the nitrogen-containing gas
- IB-1-3. Using NF3 as the nitrogen-containing gas
- IB-1-4. Using NOx as the nitrogen-containing gas
- IB-1-5. Using Nitrogen oxide as the nitrogen-containing gas
- IB-1-6. Using Nitrogen and Helium mixture as the nitrogen-containing gas

Should Applicant elected the invention of IB-2 (plasma source) within IB, then one of the following species must be elected:

- IB-2-1. Downstream microwave system
- IB-2-2. Electron cyclotron residence system
- IB-2-3. Inductive coupled plasma system
- IB-2-4. Radio frequency system
- IB-2-5. Remote microwave plasma source

Should Applicant elected the invention of Group II, then one from each of the following groups must be elected:

IIA. Method for forming silicon layer (see specification, pp. 2, 6-7)

IIA-1. PECVD

IIA-2. LPCVD

IIA-3. RTCVD

IIA-4. Thermal CVD

IIA-5. CVD

- IIB. Method for forming nitride barrier layer (See specification, pp. 7)
  - IIB-1. by thermally annealing in nitrogen-containing species (i.e., see abstract section)
  - IIB-2. by exposing to plasma source (i.e., see abstract section)
- IIC. Silicon (See specification, pp. 2, 6)

IIC-1. Polysilicon

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IIC-2. Amorphous silicon

IID. Dielectric layer (See specification, pp. 6)

IID-1. Silicon dioxide

IID-2. Tantalum pentoxide

IID-3. Hafnium dioxide

IID-4. Aluminum trioxide

IIE. Silicon source materials (See specification, pp. 6)

IIE-1. SiH2

IIE-2. Si2H7

IIE-3. SiH2Cl2

IIE-4. SiCl4

IIE-5. SiH4

IIE-5. Si2H6

Currently, no claim is generic to the invention of Group II. Applicant is referred to MPEP 806.04(c) and 806.04(d) for the definition of a generic claim.

Should Applicant elected the invention of IIB-1 (Nitrogen-containing gases) within IIB, then one of the following species must be elected:

IIB-1-1. Using N2 as the nitrogen-containing gas

IIB-1-2. Using NH3 as the nitrogen-containing gas

IIB-1-3. Using NF3 as the nitrogen-containing gas

IIB-1-4. Using NOx as the nitrogen-containing gas

IIB-1-5. Using Nitrogen oxide as the nitrogen-containing gas

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IIB-1-6. Using Nitrogen and Helium mixture as the nitrogen-containing gas

Should Applicant elected the invention of IIB-2 (plasma source) within IIB, then one of the following species must be elected:

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IIB-2-1. Downstream microwave system

IIB-2-2. Electron cyclotron residence system

IIB-2-3. Inductive coupled plasma system

IIB-2-4. Radio frequency system

IIB-2-5. Remote microwave plasma source

Should Applicant elected the invention of Group III, then one from each of the following groups must be elected:

IIIA. Method for forming silicon layer (see specification, pp. 2, 6-7)

IIIA-1. PECVD

IIIA-2. LPCVD

IIIA-3. RTCVD

IIIA-4. Thermal CVD

IIIA-5. CVD

IIIB. Method for forming nitride barrier layer (See specification, pp. 7)

IIIB-1. by thermally annealing in nitrogen-containing species (i.e., see abstract section)

IIIB-2. by exposing to plasma source (i.e., see abstract section)

IIIC. Silicon (See specification, pp. 2, 6)

IIIC-1. Polysilicon

IIIC-2. Amorphous silicon

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IIID. Gate dielectric/oxide (See specification, pp. 6)

IIID-1. Silicon dioxide

IIID-2. Tantalum pentoxide

IIID-3. Hafnium dioxide

IIID-4. Aluminum trioxide

IIIE. Silicon source materials (See specification, pp. 6)

IIIE-1. SiH2

IIIE-2. Si2H7

IIIE-3. SiH2Cl2

IIIE-4. SiCl4

IIIE-5. SiH4

IIIE-5. Si2H6

IIIF Gate stacks (see specification, pp. 7-8)

IIIG-1. Oxide/nitride/polysilicon

IIIG-2. Oxide/nitride/polysilicon/nitride

IIIG-3. Oxide/nitride/polysilicon/barrier

IIIG-4. Oxide/nitride/polysilicon/barrier/metal

IIIG-5. Oxide/nitride/polysilicon/barrier/metal/nitride

IIIG-6. Oxide/nitride/polysilicon/metal silicide

IIIG-7. Oxide/nitride/polysilicon/metal silicide/nitride

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Currently, no claim is generic to the invention of Group III. Applicant is referred to MPEP 806.04(c) and 806.04(d) for the definition of a generic claim.

Should Applicant elected the invention of IIIB-1 (Nitrogen-containing gases) within IIIB, then one of the following species must be elected:

- IIIB-1-1. Using N2 as the nitrogen-containing gas
- IIIB-1-2. Using NH3 as the nitrogen-containing gas
- IIIB-1-3. Using NF3 as the nitrogen-containing gas
- IIIB-1-4. Using NOx as the nitrogen-containing gas
- IIIB-1-5. Using Nitrogen oxide as the nitrogen-containing gas
- IIIB-1-6. Using Nitrogen and Helium mixture as the nitrogen-containing gas

Should Applicant elected the invention of IIIB-2 (plasma source) within IIIB, then one of the following species must be elected:

- IIIB-2-1. Downstream microwave system
- IIIB-2-2. Electron cyclotron residence system
- IIIB-2-3. Inductive coupled plasma system
- IIIB-2-4. Radio frequency system
- IIIB-2-5. Remote microwave plasma source

Applicant is required under 35 U.S.C. 121 to elect a single disclosed species for prosecution on the merits to which the claims shall be restricted if no generic claim is finally held to be allowable.

Applicant is advised that a reply to this requirement must include an identification of the species that is elected consonant with this requirement, and a listing of all claims readable

thereon, including any claims subsequently added. An argument that a claim is allowable or that all claims are generic is considered nonresponsive unless accompanied by an election.

Upon the allowance of a generic claim, applicant will be entitled to consideration of claims to additional species which are written in dependent form or otherwise include all the limitations of an allowed generic claim as provided by 37 CFR 1.141. If claims are added after the election, applicant must indicate which are readable upon the elected species. MPEP § 809.02(a).

Should applicant traverse on the ground that the species are not patentably distinct, applicant should submit evidence or identify such evidence now of record showing the species to be obvious variants or clearly admit on the record that this is the case. In either instance, if the examiner finds one of the inventions unpatentable over the prior art, the evidence or admission may be used in a rejection under 35 U.S.C. 103(a) of the other invention.

Applicant is advised that the reply to this requirement to be complete must include an election of the invention to be examined even though the requirement be traversed (37 CFR 1.143).

6. Applicant is reminded that upon the cancellation of claims to a non-elected invention, the inventorship must be amended in compliance with 37 CFR 1.48(b) if one or more of the currently named inventors is no longer an inventor of at least one claim remaining in the application. Any amendment of inventorship must be accompanied by a request under 37 CFR 1.48(b) and by the fee required under 37 CFR 1.17(i).

Any inquiry concerning this communication or earlier communications from the examiner should be directed to Jack Chen whose telephone number is (571)272-1689. The examiner can normally be reached on Monday-Friday (9:00am-6:30pm) alternate Monday off.

If attempts to reach the examiner by telephone are unsuccessful, the examiner's supervisor, Carl W Whitehead can be reached on (571)272-1702. The fax phone number for the organization where this application or proceeding is assigned is 703-872-9306.

Information regarding the status of an application may be obtained from the Patent Application Information Retrieval (PAIR) system. Status information for published applications may be obtained from either Private PAIR or Public PAIR. Status information for unpublished applications is available through Private PAIR only. For more information about the PAIR system, see http://pair-direct.uspto.gov. Should you have questions on access to the Private PAIR system, contact the Electronic Business Center (EBC) at 866-217-9197 (toll-free).

Jack Chen

Primary Examiner
Art Unit 2813

Porcel